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Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Product Status	Active
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I <sup>2</sup> C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	25
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-VFQFN Exposed Pad
Supplier Device Package	•
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af6266uay

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

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## 1 Introduction

This datasheet refers to the STM8AF6246, STM8AF6248, STM8AF6266 and STM8AF6268 products with 16 to 32 Kbyte of Flash program memory.

In the order code, the letter 'F' refers to product versions with data EEPROM and 'H' refers to product versions without data EEPROM. The identifiers 'F' and 'H' do not coexist in a given order code.

The datasheet contains the description of family features, pinout, electrical characteristics, mechanical data and ordering information.

- For complete information on the STM8A microcontroller memory, registers and peripherals, please refer to STM8S series and STM8AF series 8-bit microcontrollers reference manual (RM0016).
- For information on programming, erasing and protection of the internal Flash memory please refer to the STM8 Flash programming manual (PM0051).
- For information on the debug and SWIM (single wire interface module) refer to the STM8 SWIM communication protocol and debug module user manual (UM0470).
- For information on the STM8 core, please refer to the STM8 CPU programming manual (PM0044).



# 3 Product line-up

Order code	Package	Medium density Flash program memory (byte)	RAM (byte)	Data EE (byte)	10-bit A/D ch.	Timers (IC/OC/PWM)	Serial interfaces	l/0 wakeup pins
STM8AF/P6268	LQFP48	32 K		1 K		1x8-bit: TIM4 3x16-bit: TIM1,	LIN(UART),	
STM8AF/P6248	(7x7)	16 K		0.5 K	10	TIM2, TIM3 (9/9/9)	SPI, I <sup>2</sup> C	38/35
STM8AF/P6266	32 K		1 K		1x8-bit: TIM4			
STM8AF/P6246	LQFP32 (7x7)	16 K	2 K	0.5 K	7	3x16-bit: TIM1, TIM2, TIM3 (8/8/8)	LIN(UART), SPI, I²C	25/23
STM8AF/P6266		32 K		1 K		1x8-bit: TIM4		
STM8AF/P6246	VFQFPN32	16 K		0.5 K	7	3x16-bit: TIM1, TIM2, TIM3 (8/8/8)	LIN(UART), SPI, I²C	25/23

### Table 1. STM8AF6246/48/66/68 product line-up



## 5.6 Low-power operating modes

For efficient power management, the application can be put in one of four different low power modes. Users can configure each mode to obtain the best compromise between lowest power consumption, fastest start-up time and available wakeup sources.

Wait mode

In this mode, the CPU is stopped but peripherals are kept running. The wakeup is performed by an internal or external interrupt or reset.

• Active-halt mode with regulator on

In this mode, the CPU and peripheral clocks are stopped. An internal wakeup is generated at programmable intervals by the auto wake up unit (AWU). The main voltage regulator is kept powered on, so current consumption is higher than in Active-halt mode with regulator off, but the wakeup time is faster. Wakeup is triggered by the internal AWU interrupt, external interrupt or reset.

• Active-halt mode with regulator off

This mode is the same as Active-halt with regulator on, except that the main voltage regulator is powered off, so the wake up time is slower.

Halt mode

CPU and peripheral clocks are stopped, the main voltage regulator is powered off. Wakeup is triggered by external event or reset.

In all modes the CPU and peripherals remain permanently powered on, the system clock is applied only to selected modules. The RAM content is preserved and the brown-out reset circuit remains activated.

## 5.7 Timers

### 5.7.1 Watchdog timers

The watchdog system is based on two independent timers providing maximum security to the applications. The watchdog timer activity is controlled by the application program or option bytes. Once the watchdog is activated, it cannot be disabled by the user program without going through reset.

#### Window watchdog timer

The window watchdog is used to detect the occurrence of a software fault, usually generated by external interferences or by unexpected logical conditions, which cause the application program to abandon its normal sequence.

The window function can be used to trim the watchdog behavior to match the application timing perfectly. The application software must refresh the counter before time-out and during a limited time window. If the counter is refreshed outside this time window, a reset is issued.



### 5.9.1 Serial peripheral interface (SPI)

The devices covered by this datasheet contain one SPI. The SPI is available on all the supported packages.

- Maximum speed: 10 Mbit/s or f<sub>MASTER</sub>/2 both for master and slave
- Full duplex synchronous transfers
- Simplex synchronous transfers on two lines with a possible bidirectional data line
- Master or slave operation selectable by hardware or software
- CRC calculation
- 1 byte Tx and Rx buffer
- Slave mode/master mode management by hardware or software for both master and slave
- Programmable clock polarity and phase
- Programmable data order with MSB-first or LSB-first shifting
- Dedicated transmission and reception flags with interrupt capability
- SPI bus busy status flag
- Hardware CRC feature for reliable communication:
  - CRC value can be transmitted as last byte in Tx mode
  - CRC error checking for last received byte

## 5.9.2 Inter integrated circuit (I<sup>2</sup>C) interface

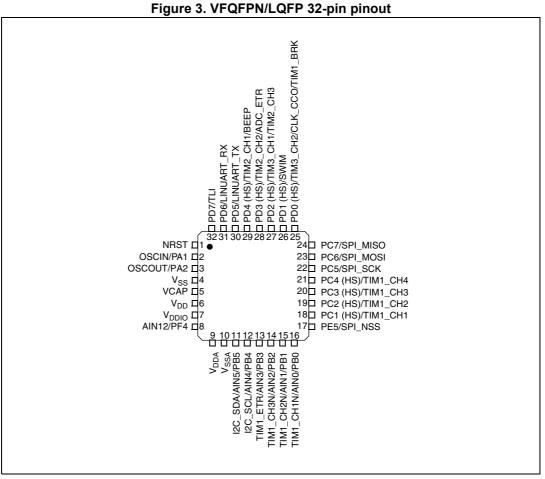
The devices covered by this datasheet contain one  $I^2C$  interface. The interface is available on all the supported packages.

- I<sup>2</sup>C master features:
  - Clock generation
  - Start and stop generation
- I<sup>2</sup>C slave features:
  - Programmable I<sup>2</sup>C address detection
  - Stop bit detection
- Generation and detection of 7-bit/10-bit addressing and general call
- Supports different communication speeds:
  - Standard speed (up to 100 kHz),
  - Fast speed (up to 400 kHz)
- Status flags:
  - Transmitter/receiver mode flag
  - End-of-byte transmission flag
  - I<sup>2</sup>C busy flag
- Error flags:
  - Arbitration lost condition for master mode
  - Acknowledgment failure after address/data transmission
  - Detection of misplaced start or stop condition
  - Overrun/underrun if clock stretching is disabled



## 6 Pinouts and pin description

## 6.1 Package pinouts



1. (HS) high sink capability.



Address	Block	Register label	Register name	Reset status		
0x00 50F3	BEEP	BEEP_CSR	BEEP control/status register	0x1F		
0x00 50F4 to 0x00 50FF		Re	eserved area (12 bytes)			
0x00 5200		SPI_CR1	SPI control register 1	0x00		
0x00 5201		SPI_CR2	SPI control register 2	0x00		
0x00 5202		SPI_ICR	SPI interrupt control register	0x00		
0x00 5203	SPI	SPI_SR	SPI status register	0x02		
0x00 5204		SPI_DR	SPI data register	0x00		
0x00 5205		SPI_CRCPR	SPI CRC polynomial register	0x07		
0x00 5206		SPI_RXCRCR	SPI Rx CRC register	0xFF		
0x00 5207		SPI_TXCRCR	SPI Tx CRC register	0xFF		
0x00 5208 to 0x00 520F	Reserved area (8 bytes)					
0x00 5210		I2C_CR1	I2C control register 1	0x00		
0x00 5211		I2C_CR2	I2C control register 2	0x00		
0x00 5212		I2C_FREQR	I2C frequency register	0x00		
0x00 5213		I2C_OARL	I2C own address register low	0x00		
0x00 5214		I2C_OARH	I2C own address register high	0x00		
0x00 5215			Reserved area (1 byte)			
0x00 5216	I2C	I2C_DR	I2C data register	0x00		
0x00 5217	120	I2C_SR1	I2C status register 1	0x00		
0x00 5218		I2C_SR2	I2C status register 2	0x00		
0x00 5219		I2C_SR3	I2C status register 3	0x00		
0x00 521A		I2C_ITR	I2C interrupt control register	0x00		
0x00 521B		I2C_CCRL	I2C clock control register low	0x00		
0x00 521C		I2C_CCRH	I2C clock control register high	0x00		
0x00 521D		I2C_TRISER	I2C TRISE register	0x02		
0x00 521E to 0x00 523F	Reserved area (24 bytes)					

#### Table 11. General hardware register map (continued)



	Table 11. General hardware register map (continued)							
Address	Block	Register label	Register name	Reset status				
0x00 5240		UART2_SR	LINUART status register	0xC0				
0x00 5241		UART2_DR	LINUART data register	0xXX				
0x00 5242		UART2_BRR1	LINUART baud rate register 1	0x00				
0x00 5243		UART2_BRR2	LINUART baud rate register 2	0x00				
0x00 5244	LINUART	UART2_CR1	LINUART control register 1	0x00				
0x00 5245		UART2_CR2	LINUART control register 2	0x00				
0x00 5246		UART2_CR3	LINUART control register 3	0x00				
0x00 5247		UART2_CR4	LINUART control register 4	0x00				
0x00 5248			Reserved					
0x00 5249		UART2_CR6	LINUART control register 6	0x00				
0x00 524A to 0x00 524F		Reserved area (6 bytes)						
0x00 5250		TIM1_CR1	TIM1 control register 1	0x00				
0x00 5251		TIM1_CR2	TIM1 control register 2	0x00				
0x00 5252		TIM1_SMCR	TIM1 slave mode control register	0x00				
0x00 5253		TIM1_ETR	TIM1 external trigger register	0x00				
0x00 5254		TIM1_IER	TIM1 Interrupt enable register	0x00				
0x00 5255		TIM1_SR1	TIM1 status register 1	0x00				
0x00 5256		TIM1_SR2	TIM1 status register 2	0x00				
0x00 5257		TIM1_EGR	TIM1 event generation register	0x00				
0x00 5258		TIM1_CCMR1	TIM1 capture/compare mode register 1	0x00				
0x00 5259		TIM1_CCMR2	TIM1 capture/compare mode register 2	0x00				
0x00 525A		TIM1_CCMR3	TIM1 capture/compare mode register 3	0x00				
0x00 525B	TIM1	TIM1_CCMR4	TIM1 capture/compare mode register 4	0x00				
0x00 525C		TIM1_CCER1	TIM1 capture/compare enable register 1	0x00				
0x00 525D		TIM1_CCER2	TIM1 capture/compare enable register 2	0x00				
0x00 525E		TIM1_CNTRH	TIM1 counter high	0x00				
0x00 525F		TIM1_CNTRL	TIM1 counter low	0x00				
0x00 5260		TIM1_PSCRH	TIM1 prescaler register high	0x00				
0x00 5261		TIM1_PSCRL	TIM1 prescaler register low	0x00				
0x00 5262		TIM1_ARRH	TIM1 auto-reload register high	0xFF				
0x00 5263		TIM1_ARRL	TIM1 auto-reload register low	0xFF				
0x00 5264		TIM1_RCR	TIM1 repetition counter register	0x00				

 Table 11. General hardware register map (continued)



## 8 Interrupt table

Table 14. STM8A Interrupt table						
Priority	Source block	Description	Interrupt vector address	Wakeup from Halt	Comments	
-	Reset	Reset	0x00 8000	Yes	User RESET vector	
-	TRAP	SW interrupt	0x00 8004	-	-	
0	TLI	External top level interrupt	0x00 8008	-	-	
1	AWU	Auto-wakeup from Halt	0x00 800C	Yes	-	
2	Clock controller	Main clock controller	0x00 8010	-	-	
3	MISC	Ext interrupt E0	0x00 8014	Yes	Port A interrupts	
4	MISC	Ext interrupt E1	0x00 8018	Yes	Port B interrupts	
5	MISC	Ext interrupt E2	0x00 801C	Yes	Port C interrupts	
6	MISC	Ext interrupt E3	0x00 8020	Yes	Port D interrupts	
7	MISC	Ext interrupt E4	0x00 8024	Yes	Port E interrupts	
8	Reserved <sup>(1)</sup>	-	-	-	-	
9	Reserved <sup>(1)</sup>	-	-	-	-	
10	SPI	End of transfer	0x00 8030	Yes	-	
11	Timer 1	Update/overflow/ trigger/break	0x00 8034	-	-	
12	Timer 1	Capture/compare	0x00 8038	-	-	
13	Timer 2	Update/overflow	0x00 803C	-	-	
14	Timer 2	Capture/compare	0x00 8040	-	-	
15	Timer 3	Update/overflow	0x00 8044	-	-	
16	Timer 3	Capture/compare	0x00 8048	-	-	
17	Reserved <sup>(1)</sup>	-	-	-	-	
18	Reserved <sup>(1)</sup>	-	-	-	-	
19	l <sup>2</sup> C	I <sup>2</sup> C interrupts	0x00 8054	Yes	-	
20	LINUART	Tx complete/error	0x00 8058	-	-	
21	LINUART	Receive data full reg.	0x00 805C	-	-	
22	ADC	End of conversion	0x00 8060	-	-	
23	Timer 4	Update/overflow	0x00 8064	-	-	
24	EEPROM	End of Programming/ Write in not allowed area	0x00 8068	-	-	

#### Table 14. STM8A interrupt table

1. All reserved and unused interrupts must be initialized with 'IRET' for robust programming.



## 9 Option bytes

Option bytes contain configurations for device hardware features as well as the memory protection of the device. They are stored in a dedicated block of the memory. Each option byte has to be stored twice, for redundancy, in a regular form (OPTx) and a complemented one (NOPTx), except for the ROP (read-out protection) option byte and option bytes 8 to 16.

Option bytes can be modified in ICP mode (via SWIM) by accessing the EEPROM address shown in *Table 15: Option bytes* below.

Option bytes can also be modified 'on the fly' by the application in IAP mode, except the ROP and UBC options that can only be toggled in ICP mode (via SWIM).

Refer to the STM8 Flash programming manual (PM0051) and STM8 SWIM communication protocol and debug module user manual (UM0470) for information on SWIM programming procedures.

Addr.	Option	Option		Option bits				Factory default			
Auur.	name	byte no.	7	6	5	4	3	2	1	0	setting
0x00 4800	Read-out protection (ROP)	OPT0		ROP[7:0]						0x00	
0x00 4801	User boot	OPT1	Rese	Reserved UBC[5:0]				0x00			
0x00 4802	(UBC)	NOPT1	Rese	Reserved				C[5:0]			0xFF
0x00 4803	Alternate function	OPT2	AFR7	AFR6	AFR5	AFR4	AFR3	AFR2	AFR1	AFR0	0x00
0x00 4804	remapping (AFR)	NOPT2	NAFR 7	NAFR 6	NAFR 5	NAFR 4	NAFR 3	NAFR 2	NAFR 1	NAFR 0	0xFF
0x00 4805	Watchdog	OPT3		Reserved			LSI _EN	IWDG _HW	WWDG _HW	WWDG _HALT	0x00
0x00 4806	option	NOPT3					NLSI _EN	NIWDG _HW	NWWD G_HW	NWWG _HALT	0xFF
0x00 4807	Clock	OPT4		Reserved				CKAWU SEL	PRS C1	PRS C0	0x00
0x00 4808	option	NOPT4	Reserved				NEXT CLK	NCKAW USEL	NPR SC1	NPR SC0	0xFF
0x00 4809	HSE clock	OPT5		HSECNT[7:0]						0x00	
0x00 480A	startup	NOPT5				NHSE	CNT[7:0]				0xFF

#### Table 15. Option bytes



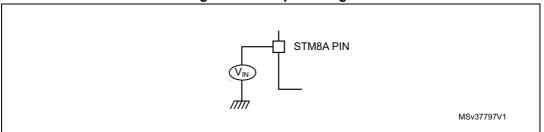
Option byte no.	Description
OPT12	TMU_KEY 5 [7:0]: Temporary unprotection key 4 Temporary unprotection key: Must be different from 0x00 or 0xFF
OPT13	TMU_KEY 6 [7:0]: Temporary unprotection key 5           Temporary unprotection key: Must be different from 0x00 or 0xFF
OPT14	TMU_KEY 7 [7:0]: Temporary unprotection key 6           Temporary unprotection key: Must be different from 0x00 or 0xFF
OPT15	TMU_KEY 8 [7:0]: Temporary unprotection key 7           Temporary unprotection key: Must be different from 0x00 or 0xFF
OPT16	TMU_MAXATT [7:0]: TMU access failure counter         TMU_MAXATT can be initialized with the desired value only if TMU is disabled (TMU[3:0]=0101 in OPT6 option byte).         When TMU is enabled, any attempt to temporary remove the readout protection by using wrong key values increments the counter.         When the option byte value reaches 0x08, the Flash memory and data EEPROM are erased.
OPT17	BL [7:0]: Bootloader enable If this option byte is set to 0x55 (complementary value 0xAA) the bootloader program is activated also in case of a programmed code memory (for more details, see the bootloader user manual, UM0560).

#### Table 16. Option byte description (continued)



### 10.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in Figure 7.



#### Figure 7. Pin input voltage

## 10.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

	U			
Symbol	Ratings	Min	Max	Unit
V <sub>DDx</sub> - V <sub>SS</sub>	Supply voltage (including $V_{DDA and} V_{DDIO}$ ) <sup>(1)</sup>	-0.3	6.5	V
V	Input voltage on true open drain pins (PE1, PE2) <sup>(2)</sup>	V <sub>SS</sub> - 0.3	6.5	V
V <sub>IN</sub>	Input voltage on any other pin <sup>(2)</sup>	V <sub>SS</sub> - 0.3	V <sub>DD</sub> + 0.3	v
V <sub>DDx</sub> - V <sub>DD</sub>	Variations between different power pins	-	50	mV
V <sub>SSx</sub> - V <sub>SS</sub>	Variations between all the different ground pins	-	50	IIIV
V <sub>ESD</sub>	Electrostatic discharge voltage		ite maximum cal sensitivity) page 76	•

Table 17. Voltage characteristics

1. All power (V<sub>DD</sub>, V<sub>DDIO</sub>, V<sub>DDA</sub>) and ground (V<sub>SS</sub>, V<sub>SSIO</sub>, V<sub>SSA</sub>) pins must always be connected to the external power supply

2. I<sub>INJ(PIN)</sub> must never be exceeded. This is implicitly insured if V<sub>IN</sub> maximum is respected. If V<sub>IN</sub> maximum cannot be respected, the injection current must be limited externally to the I<sub>INJ(PIN)</sub> value. A positive injection is induced by V<sub>IN</sub> > V<sub>DD</sub> while a negative injection is induced by V<sub>IN</sub> < V<sub>SS</sub>. For true open-drain pads, there is no positive injection current, and the corresponding V<sub>IN</sub> maximum must always be respected



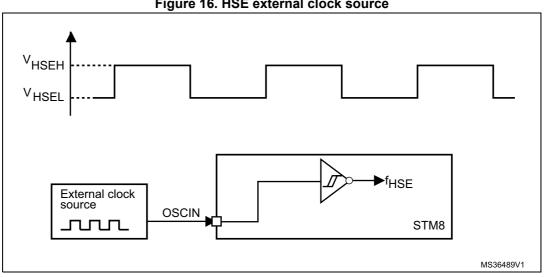


Figure 16. HSE external clock source

#### HSE crystal/ceramic resonator oscillator

The HSE clock can be supplied using a crystal/ceramic resonator oscillator of up to 16 MHz. All the information given in this paragraph is based on characterization results with specified typical external components. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details (frequency, package, accuracy...).

Table 29. HSE osci	llator characteristics
--------------------	------------------------

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R <sub>F</sub>	Feedback resistor	-	-	220	-	kΩ
$C_{L1}/C_{L2}^{(1)}$	Recommended load capacitance	-	-	-	20	pF
9 <sub>m</sub>	Oscillator transconductance	-	5	-	-	mA/V
t <sub>SU(HSE)</sub> <sup>(2)</sup>	Startup time	V <sub>DD</sub> is stabilized	-	2.8	-	ms

1. The oscillator needs two load capacitors,  $C_{L1}$  and  $C_{L2}$ , to act as load for the crystal. The total load capacitance ( $C_{load}$ ) is  $(C_{L1} * C_{L2})/(C_{L1} + C_{L2})$ . If  $C_{L1} = C_{L2}$ ,  $C_{load} = C_{L1} / 2$ . Some oscillators have built-in load capacitors,  $C_{L1}$  and  $C_{L2}$ .

2. This value is the startup time, measured from the moment it is enabled (by software) until a stabilized 16 MHz oscillation is reached. It can vary with the crystal type that is used.



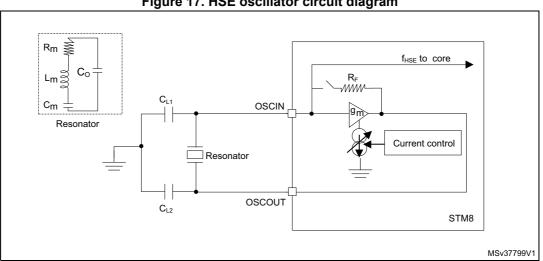


Figure 17. HSE oscillator circuit diagram

### HSE oscillator critical g<sub>m</sub> formula

The crystal characteristics have to be checked with the following formula:

g<sub>m</sub> » g<sub>mcrit</sub>

where  $g_{mcrit}$  can be calculated with the crystal parameters as follows:

$$g_{mcrit} = (2 \times \Pi \times {}^{f}HSE)^{2} \times R_{m}(2Co + C)^{2}$$

R<sub>m</sub>: Notional resistance (see crystal specification)

L<sub>m</sub>: Notional inductance (see crystal specification)

C<sub>m</sub>: Notional capacitance (see crystal specification)

Co: Shunt capacitance (see crystal specification)

 $C_{1,1} = C_{1,2} = C$ : Grounded external capacitance

#### 10.3.4 Internal clock sources and timing characteristics

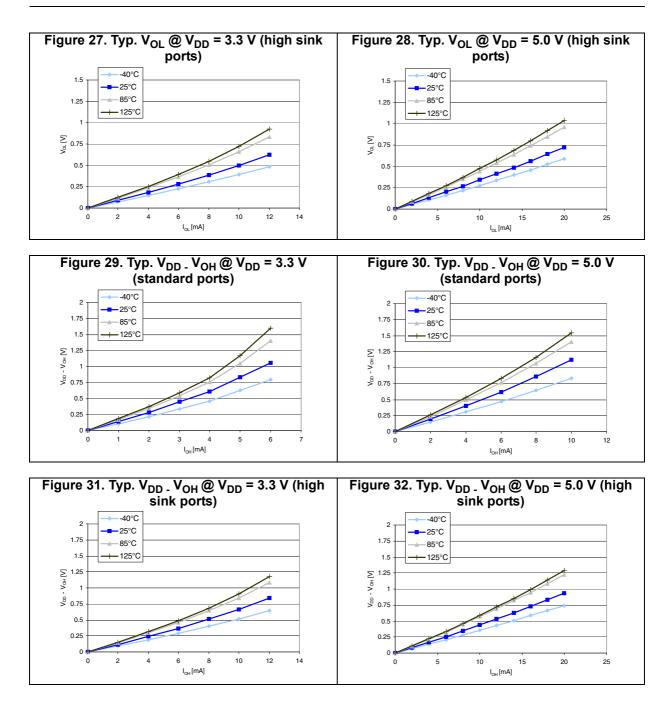
Subject to general operating conditions for V<sub>DD</sub> and T<sub>A</sub>.

#### High speed internal RC oscillator (HSI)

Table 30. HSI oscillator characteristics	Table 30.	HSI	oscillator	characteristics
--	-----------	-----	------------	-----------------

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
f <sub>HSI</sub>	Frequency	-	-	16	-	MHz







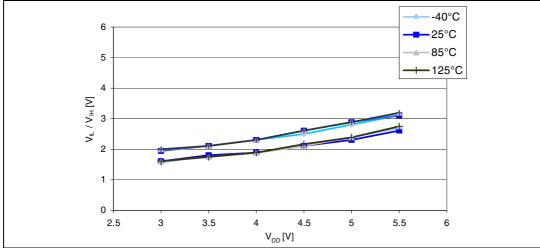
## 10.3.7 Reset pin characteristics

Subject to general operating conditions for  $V_{\text{DD}}$  and  $T_{\text{A}}$  unless otherwise specified.

		-				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>IL(NRST)</sub>	NRST input low level voltage <sup>(1)</sup>	-	$V_{SS}$	-	$0.3 \times V_{DD}$	
V <sub>IH(NRST)</sub>	NRST input high level voltage <sup>(1)</sup>	-	$0.7  ext{ x V}_{ ext{DD}}$	-	V <sub>DD</sub>	V
V <sub>OL(NRST)</sub>	NRST output low level voltage <sup>(1)</sup>	I <sub>OL</sub> = 3 mA	-	-	0.6	
R <sub>PU(NRST)</sub>	NRST pull-up resistor	-	30	40	60	kΩ
t <sub>IFP</sub>	NRST input filtered pulse <sup>(1)</sup>	-	85	-	315	
t <sub>INFP(NRST)</sub>	NRST Input not filtered pulse duration <sup>(2)</sup>	-	500	-	-	ns

1. Data based on characterization results, not tested in production.

2. Data guaranteed by design, not tested in production.



## Figure 33. Typical NRST $V_{IL}$ and $V_{IH}$ vs $V_{DD}$ @ four temperatures



### 10.3.8 TIM 1, 2, 3, and 4 timer specifications

Subject to general operating conditions for  $V_{\text{DD}},\,f_{\text{MASTER}},$  and  $T_{\text{A}}$  unless otherwise specified.

Table 37. TIM 1	2, 3, and 4 electrical specified	ications
-----------------	----------------------------------	----------

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
f <sub>EXT</sub>	Timer external clock frequency <sup>(1)</sup>	-	-	-	16	MHz

1. Not tested in production. On 64 Kbyte devices, the frequency is limited to 16 MHz.

#### 10.3.9 SPI serial peripheral interface

Unless otherwise specified, the parameters given in *Table 38* are derived from tests performed under ambient temperature,  $f_{MASTER}$  frequency and  $V_{DD}$  supply voltage conditions.  $t_{MASTER} = 1/f_{MASTER}$ .

Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Symbol	Parameter	Conditions		Min	Мах	Unit
		Master mode		0	10	
f <sub>SCK</sub> 1/t <sub>c(SCK)</sub>	SPI clock frequency	Slave mode	V <sub>DD</sub> < 4.5 V	0	6 <sup>(1)</sup>	MHz
		Slave mode	V <sub>DD</sub> = 4.5 V to 5.5 V	0	8 <sup>(1)</sup>	
t <sub>r(SCK</sub> ) t <sub>f(SCK)</sub>	SPI clock rise and fall time	Capacitive load: C = 30 pF		-	25 <sup>(2)</sup>	
t <sub>su(NSS)</sub> <sup>(3)</sup>	NSS setup time	Slave mode		4 * t <sub>MASTER</sub>	-	
t <sub>h(NSS)</sub> <sup>(3)</sup>	NSS hold time	Slave mode		70	-	
t <sub>w(SCKH)</sub> <sup>(3)</sup> t <sub>w(SCKL)</sub> <sup>(3)</sup>	SCK high and low time	Master mode		t <sub>SCK</sub> /2 - 15	t <sub>SCK</sub> /2 + 15	
t <sub>su(MI)</sub> (3)	Data input setup time	Master mode		5	-	-
$t_{su(SI)}^{(3)}$	Data input setup time	Slave mode		5	-	
t <sub>h(MI)</sub> (3)	Data input hold time	Master mode		7	-	ns
t <sub>h(MI)</sub> (3) t <sub>h(SI)</sub> (3)	Data input hold time	Slave mode		10	-	
t <sub>a(SO)</sub> (3)(4)	Data output access time	Slave mode		-	3* t <sub>MASTER</sub>	
t <sub>dis(SO)</sub> <sup>(3)(5)</sup>	Data output disable time	Slave mode		25		
+ (3)	Data autaut valid tima	Slave mode	V <sub>DD</sub> < 4.5 V	-	75	
t <sub>v(SO)</sub> <sup>(3)</sup>	Data output valid time	(after enable edge) $V_{DD} = 4.5 \text{ V to } 5.5 \text{ V}$		-	53	
t <sub>v(MO)</sub> <sup>(3)</sup>	Data output valid time	Master mode (after enable edge)		-	30	
t <sub>h(SO)</sub> <sup>(3)</sup>	Data output hold time	Slave mode (after e	nable edge)	31	-	
t <sub>h(MO)</sub> <sup>(3)</sup>	Data output hold time	Master mode (after enable edge)		12	-	

Table 38. SPI ch	aracteristics
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1.  $f_{SCK} < f_{MASTER}/2$ .

2. The pad has to be configured accordingly (fast mode).



### 10.3.12 EMC characteristics

Susceptibility tests are performed on a sample basis during product characterization.

#### Functional EMS (electromagnetic susceptibility)

While executing a simple application (toggling 2 LEDs through I/O ports), the product is stressed by two electromagnetic events until a failure occurs (indicated by the LEDs).

- **ESD**: Electrostatic discharge (positive and negative) is applied on all pins of the device until a functional disturbance occurs. This test conforms with the IEC 1000-4-2 standard.
- FTB: A burst of fast transient voltage (positive and negative) is applied to V<sub>DD</sub> and V<sub>SS</sub> through a 100 pF capacitor, until a functional disturbance occurs. This test conforms with the IEC 1000-4-4 standard.

A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709.

#### Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

#### Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical data corruption (control registers...)

#### Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be recovered by applying a low state on the NRST pin or the oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Symbol	Parameter	Conditions	Level/class
V <sub>FESD</sub>	Voltage limits to be applied on any I/O pin to induce a functional disturbance	$V_{DD}$ = 3.3 V, T <sub>A</sub> = 25 °C, f <sub>MASTER</sub> = 16 MHz (HSI clock), Conforms to IEC 1000-4-2	3/B
V <sub>EFTB</sub>	Fast transient voltage burst limits to be applied through 100 pF on $V_{DD}$ and $V_{SS}$ pins to induce a functional disturbance	$V_{DD}$ = 3.3 V, $T_A$ = 25 °C, f <sub>MASTER</sub> = 16 MHz (HSI clock), Conforms to IEC 1000-4-4	4/A

Table	12	EMC	data
rable	4Z.		uala



#### Static latch-up

Two complementary static tests are required on 10 parts to assess the latch-up performance.

- A supply overvoltage (applied to each power supply pin) and
- A current injection (applied to each input, output and configurable I/O pin) are performed on each sample.

This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

Symbol	Parameter	Conditions	Class <sup>(1)</sup>
		$T_A = 25 \ ^\circ C$	
LU	Static lateb up along	T <sub>A</sub> = 85 °C	٨
LU	Static latch-up class	T <sub>A</sub> = 125 °C	A
	-	T <sub>A</sub> = 150 °C	

Table 4	5. Electrical	sensitivities
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 Class description: A Class is an STMicroelectronics internal specification. All its limits are higher than the JEDEC specifications, that means when a device belongs to class A it exceeds the JEDEC standard. B class strictly covers all the JEDEC criteria (international standard).



## 11.2 LQFP48 package information

SEATING PLANE A2 ŨŦŨŦŨŦŨŦĬĦŮ<del>Ÿ</del>ŨŦŨŦŨŦŨŦŎŹ F 0.25 mm GAUGE PLANE ĸ D A1 D1 L1 D3 24 37 Œ b Œ <u>ш</u> ш Ē ----------£ 48 13 12 e 5B\_ME\_V2

Figure 45. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package outline

1. Drawing is not to scale.

